MDP 4070
MONITORING DEVICE 9 kHz to 400 MHz

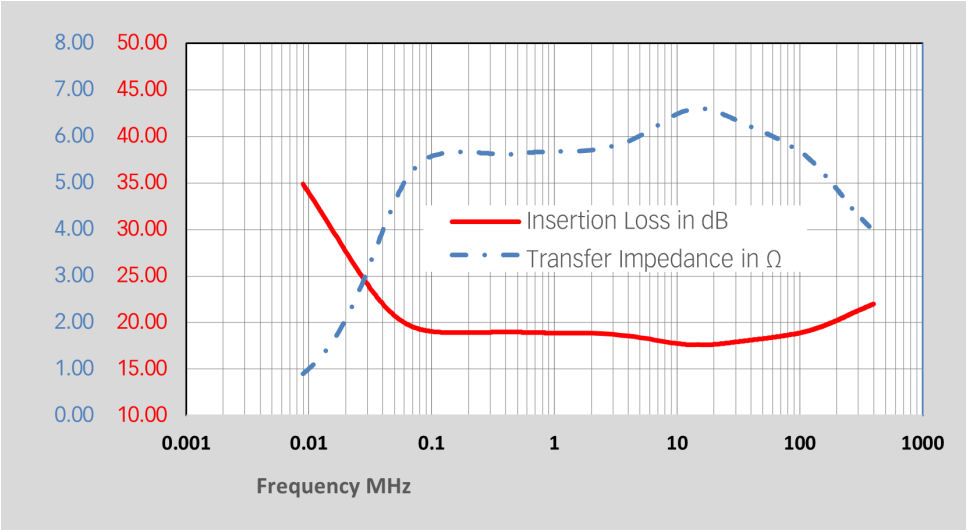
The monitoring device MDP 4070 is a passive current sensor probe can measure the current in a conductor without connecting it directly. The MDP 4070 allows fast and easy measurement as it can be quickly clamped around the current carrying conductor.

The MDP 4070 is characterized over the frequency range from 9 kHz to 400 MHz. It has, relativly, flat response in the range from 100 kHz to 100 MHz. This make conversion from voltage to current easily made with a fixed factor. It can be used for the procedure for clamp injection when the common-mode impedance requirements cannot be met given in chapter 7.4 of IEC/EN 61000-4-6 „Immunity to conducted disturbances, induced by radio frequency fields". The MDP 4070 can also be used as current monitor for BCI testing for different standards as in ISO 11452-4, RTCA/DO-160 section 20 and various automotive standards.

- **As required in IEC/EN 61000-4-6**
- **Suitable for BCI testing per ISO 11452-4, RTCA/DO-160 section 20 and various automotive standards**
- **Flat frequency response**
- **Ruggedly designed**

Technical specifications

Frequency range:	9 kHz to 400 MHz
Insertion Loss:	typical 18.5dB ±3 dB (50 Ω system, 100 kHz to 100 MHz)
Transfer impedance:	see graph for typical values
Signal output:	Type-N, jack (female)
Max. signal current (DC,50/60 Hz)	3 A
Max. signal current (RF)	500 mA



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MD 4070A
MONITORING DEVICE 4 kHz to 400 MHz

MDP 4070 in suitcase

Environmental conditions

Classification:	Indoor use only
Operating temperature:	0°C to +40 °C
Storage and transport temperature:	-10°C to +60 °C
Relative humidity:	up to 90% (no moisture condensation)

Mechanical specification of the probe

Aperture, window diameter	25.4 mm (1.0 in)
Diemensions (L x W x D):	105 x 82 x 38 mm³
Free cable diameter:	23 mm
Weight:	approx. 525 g

Model No. and options

Part number	Description
253904	MDP 4070A Monitoring device (current sensing probe) passive.
97-253900	MD 4070-TC Traceable calibration (ISO17025)
98-253900	MD 4070-ACC Accredited calibration (ISO17025)
252054	FIX MD4070 Positioning fixture for MD 4070 in PCJ 9201
252052	PCJ 9201B Calibration jig for current probes, meets ISO 11452-4 ,RTCA, DO-160 section 20, MIL-STD-461 and IEC/EN 61000-4-6

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